Face Image Quality Assessment -NIST Interagency Report 8485 Specific Image Defect Detection

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FRTE/FATE Activities



	1:1 Verification	• Same person or not?				
	1:N Search	• Who is that?				
	1:N Face + Iris	Vendor-defined fusion				
Face Recognition Technology Evaluation	Twins Disambiguation	• Is it possible to avoid false positives in twins?				
	Morph Detection	• Two faces in one passport!				
	Quality Summarization	• Predict future recognition failure?				
	Quality Defect Detection	• What exactly is wrong with a face image?				
Face Analysis Technology	Presentation Attack Detection	 Is this image intended to subvert the system? 				
EVAIUALIUII	Age Estimation	How old? Old enough?				

Why Specific Image Defect Detection?



- Automated face recognition is sensitive to quality problems in images
- Standards set requirements on images
 - ➢ For MRTD, ISO/IEC:39794-5
 - For law enforcement, ANSI/NIST standard
- SIDD gives users a set of tools to check those requirements

Shadows and Lighting

Glasses

Size and Position

Resolution, Print Size, and Quality

Digital Alterations and Retouching

Pose and Expression

Attire, Hats, and Hair

Background

Children

Online Renewal Application



Acceptable- Background is white or off-white, without shadows, and is plain without texture, objects, or lines



US Passport Photo Guidelines from https://travel.state.gov/content/travel/en/passports/how-apply/photos.html



- FATE SIDD extends the Quality Assessment evaluation of algorithms that answer the question "How good is this image?"
 - This is the face equivalent of NFIQ
- We test specific image defect detectorsalgorithms that answer the question "What specifically is wrong with this image, and to what extent?"
- The two main goals of the SIDD evaluation are to support quality algorithm development and to support ISO/IEC 29794-5.



SubjectPoseYaw = 20°

MouthOpen = 0.08

BackgroundUniformity = 0.8

EyeGlassesPresent = 1

FATE SIDD Support of ISO/IEC 29794-5



Category	ISO/IEC 29794-5 Quality Check	SIDD Quality Component
	7.3.2 Background uniformity	Background uniformity
	7.3.3 Illumination uniformity	-
	7.3.4 Moments of the luminance distribution	-
	7.3.5 Under-exposure prevention	Under-exposure
Capture	7.3.6 Over-exposure prevention	Over-exposure
device-related	7.3.7 Dynamic range	-
	7.3.8 Sharpness	Resolution
	7.3.9 Motion blur prevention	Motion blur
	7.3.10 Compression ratio	Compression artifacts
	7.3.11 Natural color	-
	7.4.2 Single face present	Face count
	7.4.3 Eyes open	Eyes open
	7.4.4 Mouth closed	Mouth open
	7.4.5 Eyes visible	Sunglasses + eyeglasses
	7.4.6 Mouth occlusion prevention	Face occlusion
	7.4.7 Face occlusion prevention	Face occlusion
	7.4.8 Inter-eye distance	Inter-eye distance
Subject-related	7.4.9 Head size	Distance from eyes to edges
,	7.4.10 Crop of the face Image	Distance from eyes to edges
	7.4.11 Pose	Pose
	7.4.12 Expression neutrality	-
	7.4.13 No head covering	-

The FATE SIDD evaluation quantifies how well algorithms perform the checks detailed in ISO/IEC 29794-5.

The NIST IR 8485 SIDD Report at a Glance



NIST Internal Report NIST IR 8485	
Face Analysis Technology Evaluation (FATE) Part 11: Face Image Quality Vector Assessment Specific Image Defect Detection	
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This publication is available free of charge from: https://doi.org/10.6028/NIST.IR.8485	

Algorithm	TotalFacesPresent	SubjectPosePitch	SubjectPoseYaw	SubjectPoseRoll	EyesOpen	InterEyeDistance	MouthOpen	BackgroundUniformity	Resolution	Underexposure	Overexposure	PixelsFromEyeToLeftEdge	PixelsFromEyeToRightEdge	PixelsFromEyesToTop	PixelsFromEyesToBottom	EyeGlassesPresent	SunGlassesPresent	CompressionArtifacts	FaceOcclusion	MotionBlur	UnifiedQualityScore
dermalog-002	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y				Y
digidata-001	Y	Y	Y	Y	Y	Y	Y		Y	Y	Y										Y
igd-001	Y	Y	Y	Y		Y			Y	Y	Y	Y	Y	Y	Y						
frpkauai-000	Y	Y	Y	Y	Y	Y		Y	Y												
idemia-002	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y
neurotechnology-002	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y
neurotechnology-003	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y
rankone-005	Y	Y	Y	Y	Y	Y	Y		Y			Y	Y	Y	Y	Y	Y	Y	Y	Y	Y
seamfix-001	Y	Y	Y	Y			Y	Y	Y	Y	Y					Y	Y				
secunet-001	Y	Y	Y	Y	Y	Y	Y	Y		Y	Y										
secunet-002	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y	Y										Y

- 20 quality measures+ Unified Quality Score
- Updated on Nov 6
 - Adds results for IDEMIA, Dermalog, SeamFix
 - Replaces median absolute error with mean absolute error
 - Adds sets for manually determined pitch and yaw

- Original report released Sep. 20
- Covered algorithms submitted from Sep 2022 to Sep 2023



Capture-Related Measures

FATE SIDD Report – Results for Background Uniformity



- Images fall into three categories:
 - Uniform (plain background, no shadows)
 - Attempt at uniformity
 - Cluttered



> FRP Kauai performs best based on rank correlation



FATE SIDD Report – Results for Underexposure



ISO/IEC 29794-5 Quality Check: Under-exposure Prevention (7.3.5)

Brightness and contrast (d_1, d_2)	(0,0)	(-16,16)	(-32,32)
	(MAR)	Complete and	
		Sel	
Result of convert -brightness-contrast $d_1 x d_2$			

- The images in this set are mugshots that are synthetically underexposed
- Brightness and contrast are applied with equal magnitudes and opposite sign



IDEMIA performs best based on rank correlation

FATE SIDD Report– Results for Overexposure



Brightness and contrast (d_1, d_2)	(0,0)	(20,20)	(40,40)
Result of convert -brightness-contrast $d_1 x d_2$			



Synthetic overexposure (value of brightness and contrast)

Brightness and contrast are increased with equal magnitude and sign

 IGD and Neurotechnology perform best based on rank correlation

FATE SIDD Report – Results for Resolution



ISO/IEC 29794-5 Quality Check: Sharpness (7.3.8)

Standard deviation σ	0	2	5
Result of convert -caussian-blur Ox			



- > Original images are selected to be ideal (with no pre-existing blur)
- Various amounts of blur are applied synthetically

- Generally, algorithms report decreasing resolution for increasing values of blur
- Rank One performs best based on rank correlation

FATE SIDD Report – Results for Motion Blur



ISO/IEC 29794-5 Quality Check: Motion Blur Prevention (7.3.9)

Displacement d	0	8	16
Result of convert -motion-blur 0xd			



SIDD Component: MotionBlur: Reported motion blur vs. known amount of blur

- > Original images are selected to be ideal (with no pre-existing blue,
- Images are blurred with various values of displacement

Rank One performs best based on rank correlation

FATE SIDD Report – Results for Compression Artifacts



ISO/IEC 29794-5 Quality Check: Compression Ratio (7.3.10)



- Varying levels of compression are applied
- Lower values indicate more compression



SIDD : Reported compression vs. known degree of compression

IDEMIA performs best based on rank correlation



Subject-Related Measures



ISO/IEC 29794-5 Quality Check: Single Face Present (7.4.2)



Faces should be counted if the estimated inter-eye distance is greater than or equal to 0.02W, where W is the image width

lue			neuro False De Missed De	etechnology etection Rate etection Rate	_003 e = 0.000 te = 0.099					
l va	7 - 6 -	0.00	0.00	0.00	0.00	0.00				
teč	<u>5</u> -	0.00	0.00	0.00	0.00	0.00				
Ja	4 -	0.00	0.00	0.00	0.00	0.60				
Ę	3 -	0.00	0.00	0.00	0.67	0.00				
ŝ	2 -	0.00	0.00	1.00	0.22	0.40				
	1-	0.00	1.00	0.00	0.11	0.00				
	0 -	1.00	0.00	0.00	0.00	0.00				
			1			1				
		0	1	2	3	4				
		True value								

> There are more missed detections than false detections

Neurotechnology_003 has lowest missed detection rate

FATE SIDD Report – Results for Eyes Open



ISO/IEC 29794-5 Quality Check: Eyes Open (7.4.3)



Image from NIST Special Database 32, MEDS.

The EyesOpen measure is computed by comparing the left and right maximum apertures of the eyes, taking the minimum of the two values, and dividing the result by inter-eye distance.



FATE SIDD Report – Results for Eyes Open





- Estimated vs. known values of the ratio of eye aperture to inter-eye distance are shown. The blue line (y = x) represents perfect performance.
- The vertical line of dots at true value zero corresponds to closed eyes.
- Digidata, Idemia, Neurotechnology, and Secunet perform best by mean absolute error.

FATE SIDD Report – Results for Mouth Open



ISO/IEC 29794-5 Quality Check: Mouth Closed (7.4.4)



Image from NIST Special Database 32, MEDS.

The MouthOpen measure is the ratio of the (vertical) maximum separation of the lips to the inter-eye distance.



FATE SIDD Report – Results for Mouth Open



 Estimated vs. known values of the ratio of lip separation to inter-eye distance are shown. The blue line (y = x) represents perfect performance.

- The vertical line of dots at true value zero corresponds to closed mouths.
- Neurotechnology performs best based on mean absolute error

FATE SIDD Report- Results for Eyeglasses



ISO/IEC 29794-5 Quality Check: Eyes Visible (7.4.5)



Image from NIST Special Dataset 32, MEDS

For eyeglasses set, two categories: with eyeglasses and without eyeglasses



Neurotechnology_002 and Neurotechnology_003 perform best based on mean absolute error

FATE SIDD Report – Results for Sunglasses



ISO/IEC 29794-5 Quality Check: Eyes Visible (7.4.5)



Image from NIST Special Dataset 32, MEDS



- The sunglasses set contains images with glasses that are opaque, semi-opaque, and transparent
- Neurotechnology_003 performs best based on rank correlation

FATE SIDD Report- Results for Face Occlusion



ISO/IEC 29794-5 Quality Check: Face Occlusion (7.4.7)

Table 15. Face Occlusion Illustration. The first and third images are from NIST Special Database 32, MEDS; the second image is used with permission of the subject.



- The Face Occlusion measure is the ratio of the occluded area of the face region to the total area
- For the images in this set, the occlusion consists mostly of hair and masks



- > IDEMIA performs best based on mean absolute error.
- > Error for FTEs is set to 0.5.

FATE SIDD Report – Results for Inter-Eye Distance



ISO/IEC 29794-5 Quality Check: Inter-Eye Distance (7.4.8)



Fig. 10. Inter-eye distance is calculated by averaging the canthi for each eye and taking the distance of the two resulting points. Image from NIST Special Database 32, MEDS.

- Rank One performs best based on mean absolute error for Set 1
- ➢ IED_{3D}=(IED_{2D}) (1/cos(yaw)) will be tested in the future



- Dermalog performs best for Set 2
- Error for FTEs is set to 50 pixels.

FATE SIDD Report- Results for Distance from Eyes to Edges

ISO/IEC 29794-5 Quality Check: Head Size (7.4.9) and Crop of the Face Image (7.4.10)



Fig. 24. Image from NIST Special Database 32, MEDS.

- We compute the distance from the left edge to the closest eye-center and the distance from the right edge to the closest eye-center
- We compute the distance from the average of the eyecenters to the top and bottom of the image



> Dermalog performs best based on mean absolute error

FATE SIDD Report- Results for Pose Yaw



ISO/IEC 29794-5 Quality Check: Pose (7.4.11)



Set 3 Estimated value (degrees) idemia 002 Mean Abs. Error = 2.980-40-0--40--60-30 30 True value (degrees)

FRP Kauai performs best by mean absolute error for Yaw Set 1 and 2

- IDEMIA performs best by mean absolute error for Yaw Set 3
- ➢ For FTEs, error is set to 45 degrees.

FATE SIDD Report- Results for Pose Pitch

Set 2



ISO/IEC 29794-5 Quality Check: Pose (7.4.11)

Set 1



- Secunet_002 performs best by mean absolute error for Pitch Set 1
- FRP Kauai performs best for Set 2

Neurotechnology_002 and IDEMIA perform best for Pitch Set 3

Estimated value (degrees)

50

0

-50

-60

-20

0

True value (degrees)

-40

For all pitch sets, error for FTEs is set to 30 degrees.

Set 3

20

40

neurotechnology_003 Mean Abs, Error = 4.8

FATE SIDD Report- Results for Pose Roll



ISO/IEC 29794-5 Quality Check: Pose (7.4.11)





For Roll, IDEMIA performs best by mean absolute error

➢ Error for FTEs is set to 45 degrees.

FATE SIDD- How to Participate



Read the <u>API</u>

- Read the <u>participation agreement</u>; agree to it, sign it, scan it to PDF.
- Implement one or more image quality components enumerated in the API
- Download the FATE quality validation package; compile, link, run, check output
- tar the combined software and validation output; sign and encrypt the tar.gz
- Subscribe to FRVT news
- Visit

https://pages.nist.gov/frvt/html/frvt_quality. html and submit using the online form

NIST

Status

Quality Algorithm Performance Background Standards How to Participate Participation Agreement API Document Validation Encryption Submission Contact Information

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Face Analysis Technology Evaluation (FATE) Quality

Quality Specific Image Defect Detection (SIDD): Report | API and Concept Document | Validation | Encryption | Submit Quality Summarization: Draft Report | Participation Agreement | Concept Document | API

Status

[2023-11-06] A new version of the FATE SIDD Report is now available. It includes results for new submissions from October 2023. We have also changed median absolute error to mean absolute error and introduced two sets for manually determined pitch and yaw.

Next Steps and Further Information



- Include test for IED with nonzero yaw
- Add new algorithms; at least one more expected by December.
- Add additional sets and images
- FATE SIDD remains open; at this time, there is no time limit for participation
- For more information and updates, see <u>https://pages.nist.gov/frvt/html/frvt_quality.</u> <u>html</u>

Note on Expression Neutrality



Q: Will FATE SIDD introduce a quality measure for expression neutrality?

A: We are currently looking into test sets for expression neutrality. If expression neutrality is included, there will likely be two categoriesneutral expression and non-neutral expression.

Datasets such as M-PIE have finer categories for expression but are not sequestered, and we anticipate that developers have trained on them.



Neutral





https://www.cs.cmu.edu/afs/cs/project/PIE/MultiPie/Multi-Pie/Content.html

Questions?

For more information: Contact <u>frvt@nist.gov</u> Visit <u>https://pages.nist.gov/frvt/html/frvt_quality.html</u> View SIDD report at <u>https://pages.nist.gov/frvt/reports/quality_sidd/frvt_quality_sidd report.pdf</u>



Explanation of IED with Yaw





The implied 3D IED is $IED_{3D} = IED_{2D}/\cos\beta$.